

**Notice of References Cited**

Application/Control No.

10/527,789

Applicant(s)/Patent Under  
Reexamination  
AIKELE ET AL.

Examiner

Anita K. Alanko

Art Unit

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**U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-5,426,070	06-1995	Shaw et al.	216/2
*	B	US-5,506,175	04-1996	Zhang et al.	438/20
*	C	US-5,628,917	05-1997	MacDonald et al.	216/2
*	D	US-2001/0013630	08-2001	Cho et al.	257/419
*	E	US-5,179,499	01-1993	MacDonald et al.	361/313
*	F	US-6,767,614	07-2004	Hofmann et al.	428/166
*	G	US-6,551,944	04-2003	Fallica et al.	438/719
*	H	US-5,963,789	10-1999	Tsuchiaki, Masakatsu	438/62
*	I	US-2007/0042606	02-2007	Wang et al.	438/700
*	J	US-7,540,192	06-2009	Takeuchi et al.	73/514.32
*	K	US-6,307,247	10-2001	Davies, Robert Bruce	257/522
	L	US-			
	M	US-			

**FOREIGN PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q					
	R					
	S					
	T					

**NON-PATENT DOCUMENTS**

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)				
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